Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/801,376	LEE ET AL.	
Examiner	Art Unit	
Ajay Vasudeva	3617	

SEARCHED							
Class	Subclass	Date	Examiner				
All	updated	6/1/2006	AV				

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

(INCLUDING SEAF	RCH STRATEGY	<u>()</u>
	DATE	EXMR
		<del> </del>
	=	
		ļ
		-
		1
		+